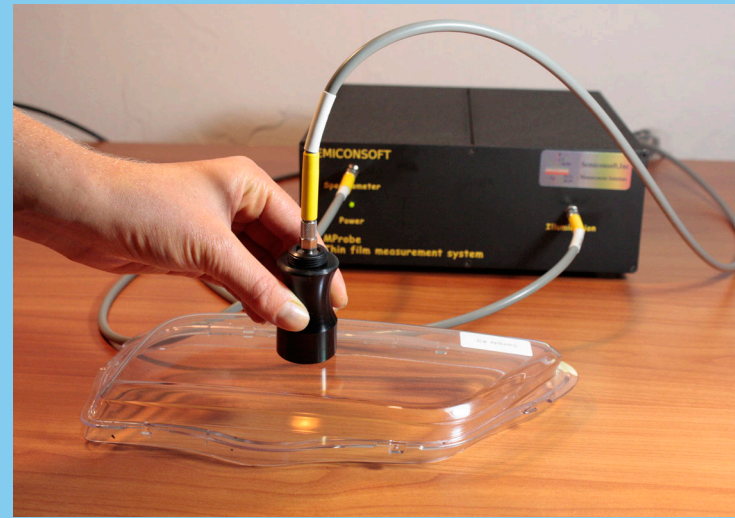




Manual Probes

For reflectance and thin-film measurement on curved surfaces

Measurements of thin films on curved sample or samples that are difficult to move (e.g. assemblies) require a special probes. These manual probes have a soft rubber padding and can be placed directly on the sample. They are connected to a measurement unit with fiberoptics cable. There are three models that can be selected depending on the application. MP-FLVis probe is targeted for applications where film is deposited on relatively thin transparent substrate and there is a need to eliminate the backside reflection (e.g there may be coating on the backside). MP- RP90 is useful in applications where 2mm spot size is acceptable and backside reflection is not a problem. MP- RP45 probe is used for measurement at an angle of incidence of 45 deg. Probes can be used for samples >1 “ in diameter



MProbe system diagram



Probe: MP-FLVis includes Vis focusing lens for <0.4 mm measurement spot size



Probe: MP- RP90 Spot size ~ 2mm. Works in wide spectral range



Probe: MP- RP45 Includes 2 quartz collimators Measurement at 45 deg angle

Probes	Work with	Used to
MP-FLVis	SMA905 terminated fiberoptics reflectance probe	Prevent backside reflectance signal for samples on > 1.5mm thick transparent substrate
MP- RP90	Ferrule (0.25”) terminated fiber-optics reflectance pro	All applications where backside reflection or spot size ~ 2mm is not a problem
MP- RP45	Two fiberoptics patch cables SMA terminated	Allows reflectance measurement at 45 deg angle